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Gerald C. Holst
Keith A. Krapels
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Joseph P. Reynolds, U.S. Army Night Vision & Electronic Sensors Directorate (United States)

Introduction

This is the 28th year for our conference, *Infrared Imaging Systems: Design, Analysis, Modeling, and Testing*. Over the years, we have witnessed the creation of IR focal plane arrays, IR scene projectors, MTF measurement techniques, and the Night Vision Integrated Performance Model (NVIPM). As government and private industry interests change, our conference has had swings in the number of papers presented and attendees. Currently, we seem to be on a rise.

We have not written an introduction to these proceedings for many years. The papers are self-explanatory and do not require any comment. We are pleased that all the authors provided professional presentations and quality manuscripts.

In 2016, our conference committee created a Best Paper Award based upon the presentation. In case of ties, the most downloaded paper is considered. We are proud to recognize:

Best presentation
David P. Haefner, Brian P. Teaney, and Bradley L. Preece, "Modeling demosaicing of color corrected cameras in the NV-IPM", Proc. SPIE 9820, Infrared Imaging Systems: Design, Analysis, Modeling, and Testing XXVII, 982009 (May 3, 2016); doi:10.1117/12.2235781.

Most downloaded paper (first 3 months after publication)
Daniel Wegner and Endre Repasi, "Image based performance analysis of thermal imagers ", Proc. SPIE 9820, Infrared Imaging Systems: Design, Analysis, Modeling, and Testing XXVII, 982016 (May 3, 2016); doi:10.1117/12.2223629.

For 2017:

Best presentation
Austin A. Richards and Martin Huebner, "A new radiometric unit of measure to characterize SWIR illumination ", Proc. SPIE 10178, Infrared Imaging Systems: Design, Analysis, Modeling, and Testing XXVIII, 101780C (May 3, 2017); doi:10.1117/12.2261459.

Most downloaded paper (first 3 months after publication)
McKenna R. Lovejoy and Mark A. Wickert, "Testing of next-generation nonlinear calibration based non-uniformity correction techniques using SWIR devices ", Proc. SPIE 10178, Infrared Imaging Systems: Design, Analysis, Modeling, and Testing XXVIII, 1017803 (May 3, 2017); doi:10.1117/12.2262127.

Thank you to all who presented, the attendees, and our excellent conference committee.

Gerald C. Holst
Keith A. Krapels